EEMF6327 - Semiconductor Device Characterization

EEMF 6327 (MSEN 6327) Semiconductor Device Characterization (3 semester credit hours) This course will describe the theoretical and practical considerations associated with the most common electrical and reliability characterization techniques used in the semiconductor industry. Prerequisite: (EEMF 6320 or MS EN 6320 or equivalent) or instructor consent required. (3-0) T (2016-02-06 00:07:04)